

MILITARY SPECIFICATION

SEMICONDUCTOR DEVICE, TRANSISTOR, NPN, SILICON, HIGH-
 POWER TYPES 2N1722, TX2N1722, 2N1724, AND TX2N1724

This amendment forms a part of Military Specification
 MIL-S-19500/262F, dated 19 February 1969, and is
 approved for use by all Departments and Agencies of
 the Department of Defense.

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Add the following new paragraph:

"4.4.4 Thermal resistance. Thermal resistance measurements shall be conducted
 in accordance with method 3131 of MIL-STD-750. The following details shall
 apply:

- a. Collector current magnitude during heating shall be 2 Adc.
- b. Collector to emitter voltage magnitude shall be 15 Vdc.
- c. The case shall be the reference temperature measuring point.
- d. Reference point temperature shall be $25^{\circ}\text{C} \leq T_R \leq 75^{\circ}\text{C}$ and recorded
 before beginning the test.
- e. Mounting arrangement shall be with heat sink to case.
- f. Maximum limit of $R_{\theta JC}$ shall be 1.5°C/W ."

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TABLE I, Subgroup 3, first Forward-current transfer ratio, Max limits column:
 Delete "90" and substitute "120".

TABLE I, Subgroup 5, Forward-current transfer ratio, Min limits column: Delete
 "18" and substitute "15".

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* TABLE II, Subgroup 2, Seal (leak-rate), Method column, delete "---" and substitute
 "1071"; Details column, delete and substitute "test condition G or H".

TABLE II, Subgroup 2, Forward-current transfer ratio, Max limits column: Delete
 "90" and substitute "120".

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TABLE III, Subgroup 2, delete Thermal resistance in its entirety and substitute the
 following:

Examination or test	MIL-STD-750		LTPD		Symbol	Limits		Unit
	Method	Details	Non TX	TX		Min	Max	
" Thermal resistance	3131	(see 4.4.4)						"

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* 4.5.6, delete and substitute:

"4.5.6 Hermetic seal (fine leak) test. All devices shall be fine-leak tested in accordance with MIL-STD-750, method 1071, test condition G or H. Maximum leak rate = 5×10^{-7} atm cm³/s."

* 4.5.6.1 and 4.5.6.2, delete in their entirety.

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* 4.5.6.3, delete and substitute:

"4.5.6.3 Hermetic seal (gross-leak) test. All devices shall be tested for gross-leak in accordance with MIL-STD-750, method 1071, test condition A, C, D, E, F, J or K."

TABLE IV, Forward-current transfer ratio, Max limits column: Delete "90" and substitute "120".

NOTE: The margin of this amendment is marked with asterisks to indicate where changes (additions, modifications, corrections, deletions) from the previous amendment were made. This was done as a convenience only and the Government assumes no liability whatsoever for any inaccuracies in these notations. Bidders and contractors are cautioned to evaluate the requirements of this document based on the entire content irrespective of the marginal notations and relationship to the last previous amendment.

Custodians:

Army - ER
Navy - EC
Air Force - 17

Preparing activity:
Army - ER

(Project 5961-0977)

Review activities:

Army - AR, MI
Navy - SH
Air Force - 11, 85, 99
DLA - ES

User activities:

Army - SM
Navy - AS, CG, MC, OS
Air Force - 19

Agent:

DLA - ES